

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10585323	TAKAHASHI ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	SHEELA C CHAWAN	2624

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	182, 181, 190, 310, 177, 187, 113, 195, 294, 176, 298, 229, 170, 182, 178, 203, 204	12/6/09	SCC
235	462.25, 462.01, 472.01 454	"	"
382	182, 190, 229	6/17/10	SCC
SEARCH UP-DATE		6/17/10	SCC
SEARCH UP-DATE		11/6/10	SCC

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
SEARCH EAST AND OTHER DATA BASE,	12/6/09	SCC
SEARCH INVENTOR NAME	12/6/09	SCC
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY	6/17/10	SCC
382/ 182, 180, 190, 310, 177, 187, 113, 195, 294, 176, 298, 229, 170, 182, 178, 203, 204.CCLS. TEXT SEARCH ONLY.	6/17/10	SCC
235/ 462.25, 462.01, 472.01, 454. CCLS. TEXT SEARCH ONLY.	6/17/10	SCC
INTERFERENCE SEARCH	6/17/10	SCC
SEARCH IEEE OR INSPEC DATA BASE.	6/17/10	SCC
SEARCH UP-DATE.	6/17/10	SCC
character recognition shooting position shooting direction character string extracting_Google search	11/6/10	SCC
SEARCH UP-DATE	11/7/10	SCC

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	182, 190, 229	6/17/10	SCC